



ALPHA & OMEGA
SEMICONDUCTOR

AOW7S65/AOWF7S65
650V 7A α MOS™ Power Transistor

General Description

The AOW7S65 & AOWF7S65 have been fabricated using the advanced α MOS™ high voltage process that is designed to deliver high levels of performance and robustness in switching applications. By providing low $R_{DS(on)}$, Q_g and E_{OSS} along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs.

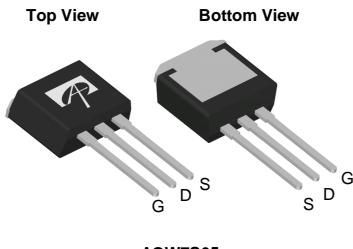
Product Summary

$V_{DS} @ T_{j,max}$	750V
I_{DM}	30A
$R_{DS(ON),max}$	0.65Ω
$Q_{g,typ}$	9.2nC
$E_{OSS} @ 400V$	2μJ

100% UIS Tested
100% R_g Tested

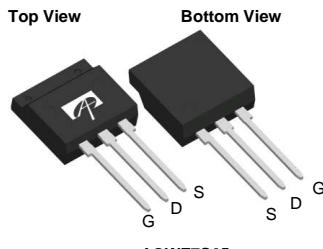


TO-262

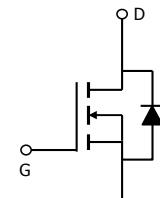


AOW7S65

TO-262F



AOWF7S65



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOW7S65	AOWF7S65	Units
Drain-Source Voltage	V_{DS}	650		V
Gate-Source Voltage	V_{GS}	± 30		V
Continuous Drain Current	I_D $T_c=25^\circ\text{C}$	7	7*	A
	I_D $T_c=100^\circ\text{C}$	5	5*	
Pulsed Drain Current ^C	I_{DM}	30		
Avalanche Current ^C	I_{AR}	1.7		A
Repetitive avalanche energy ^C	E_{AR}	43		mJ
Single pulsed avalanche energy ^G	E_{AS}	86		mJ
Power Dissipation ^B	P_D $T_c=25^\circ\text{C}$	104	25	W
	P_D Derate above 25°C	0.8	0.2	W/ $^\circ\text{C}$
MOSFET dv/dt ruggedness	dv/dt	100		V/ns
Peak diode recovery dv/dt ^H		20		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds ^J	T_L	300		°C

Thermal Characteristics

Parameter	Symbol	AOW7S65	AOWF7S65	Units
Maximum Junction-to-Ambient ^{A,D}	$R_{\theta JA}$	65	65	°C/W
Maximum Case-to-sink ^A	$R_{\theta CS}$	0.5	--	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.2	5	°C/W

* Drain current limited by maximum junction temperature.

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	650	-	-	V
		$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=150^\circ\text{C}$	700	750	-	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=650\text{V}, V_{GS}=0\text{V}$	-	-	1	μA
		$V_{DS}=520\text{V}, T_J=150^\circ\text{C}$	-	10	-	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$	-	-	± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$	2.6	3.3	4	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.5\text{A}, T_J=25^\circ\text{C}$	-	0.54	0.65	Ω
		$V_{GS}=10\text{V}, I_D=3.5\text{A}, T_J=150^\circ\text{C}$	-	1.48	1.64	Ω
V_{SD}	Diode Forward Voltage	$I_S=3.5\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	-	0.82	-	V
I_S	Maximum Body-Diode Continuous Current		-	-	7	A
I_{SM}	Maximum Body-Diode Pulsed Current ^C		-	-	30	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=100\text{V}, f=1\text{MHz}$	-	434	-	pF
C_{oss}	Output Capacitance		-	30	-	pF
$C_{o(er)}$	Effective output capacitance, energy related ^H	$V_{GS}=0\text{V}, V_{DS}=0 \text{ to } 480\text{V}, f=1\text{MHz}$	-	23	-	pF
$C_{o(tr)}$	Effective output capacitance, time related ^I		-	80	-	pF
C_{rss}	Reverse Transfer Capacitance	$V_{GS}=0\text{V}, V_{DS}=100\text{V}, f=1\text{MHz}$	-	1	-	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	-	17.5	-	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=480\text{V}, I_D=3.5\text{A}$	-	9.2	-	nC
Q_{gs}	Gate Source Charge		-	2.5	-	nC
Q_{gd}	Gate Drain Charge		-	2.7	-	nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=400\text{V}, I_D=3.5\text{A}, R_G=25\Omega$	-	21	-	ns
t_r	Turn-On Rise Time		-	14	-	ns
$t_{D(off)}$	Turn-Off DelayTime		-	55	-	ns
t_f	Turn-Off Fall Time		-	15	-	ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.5\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=400\text{V}$	-	224	-	ns
I_{rm}	Peak Reverse Recovery Current	$I_F=3.5\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=400\text{V}$	-	19	-	A
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.5\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=400\text{V}$	-	2.8	-	μC

A. The value of R_{gJA} is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$, Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{gJA} is the sum of the thermal impedance from junction to case R_{gJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

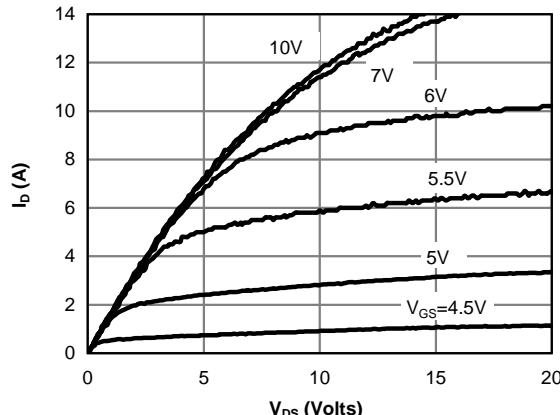
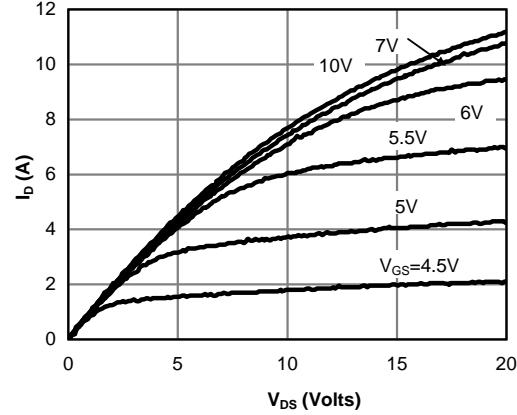
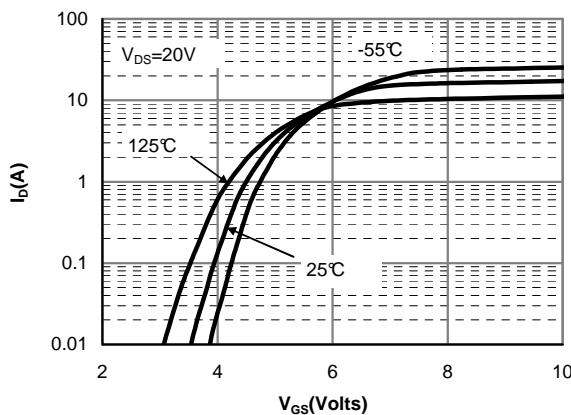
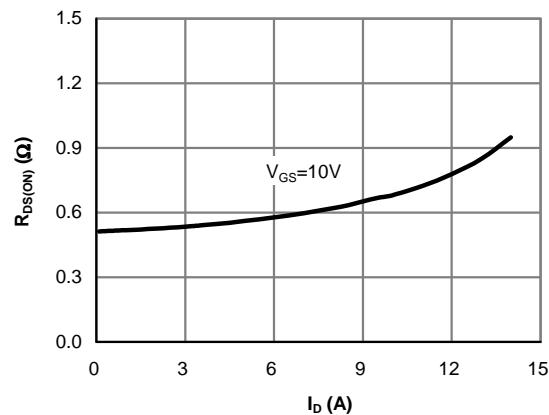
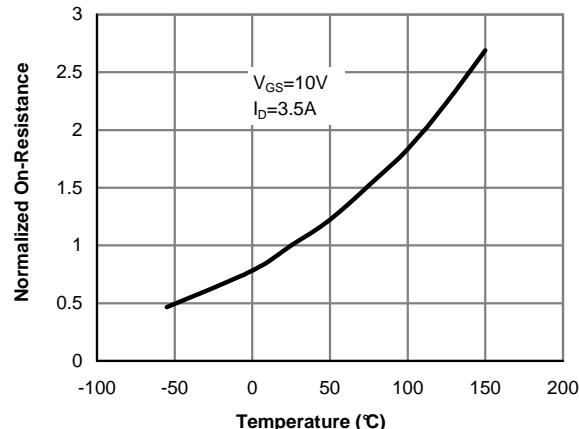
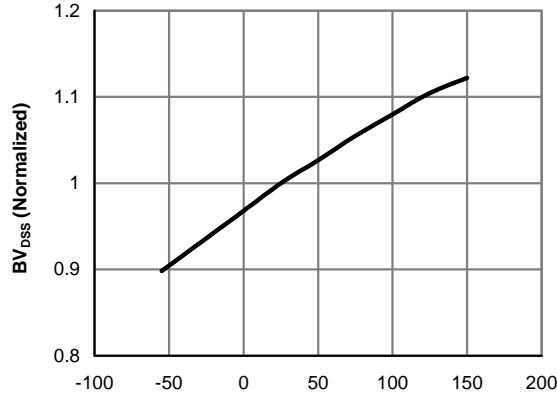
G. $L=60\text{mH}, I_{AS}=1.7\text{A}, V_{DD}=150\text{V}$, Starting $T_J=25^\circ\text{C}$

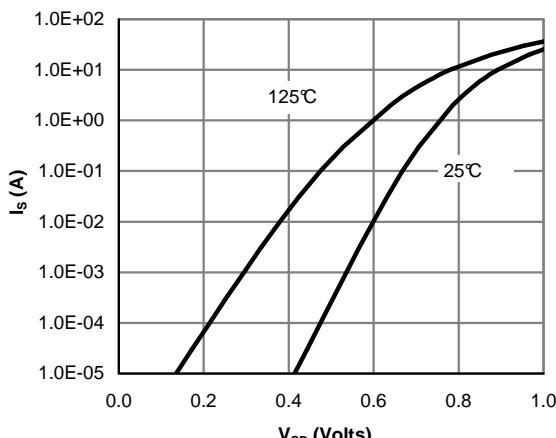
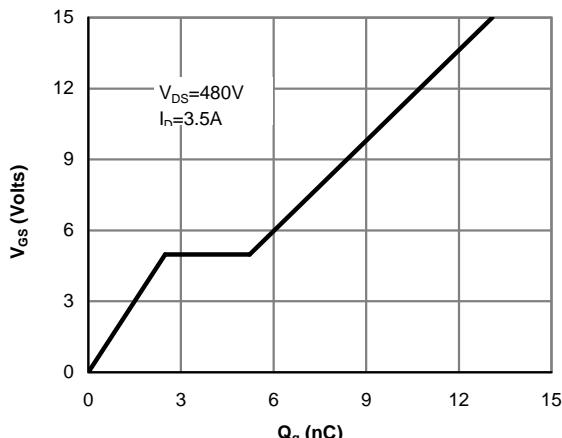
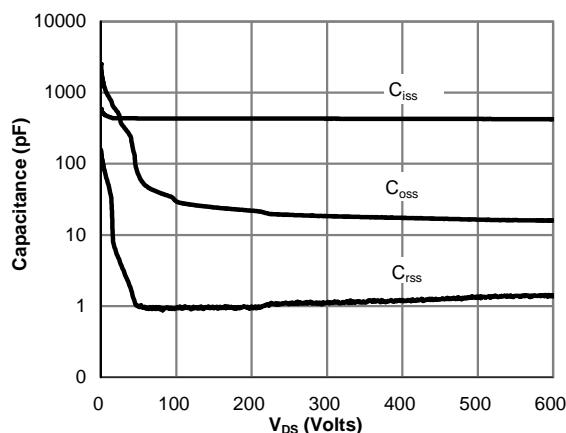
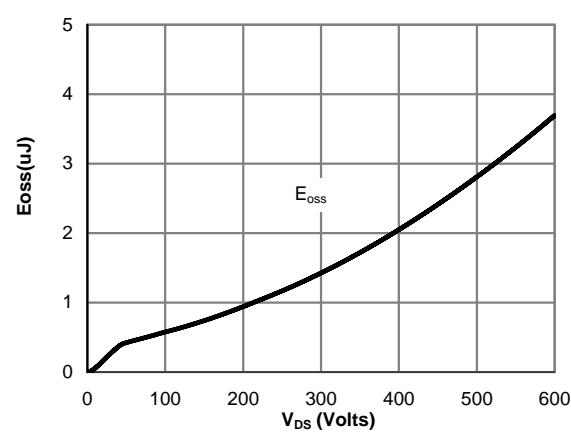
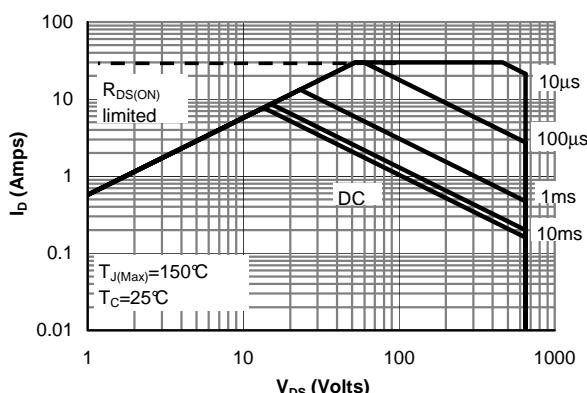
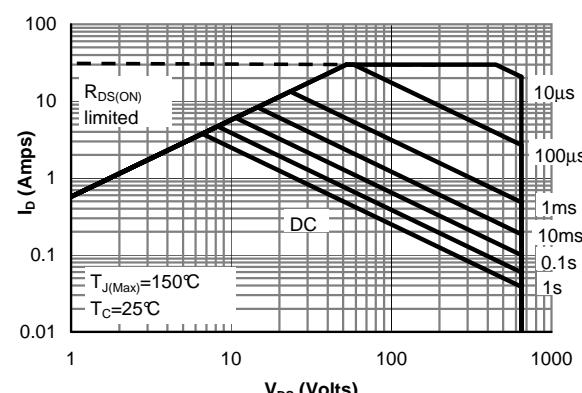
H. $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(\text{BR})DSS}$.

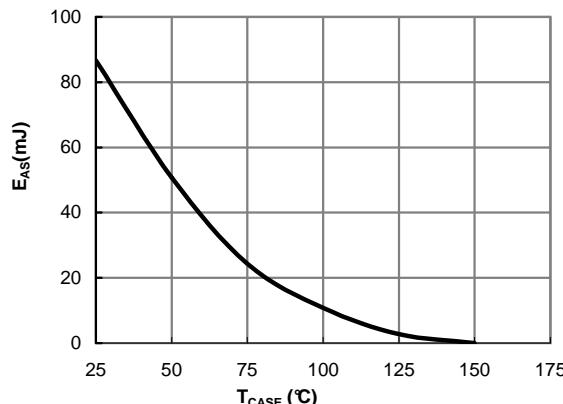
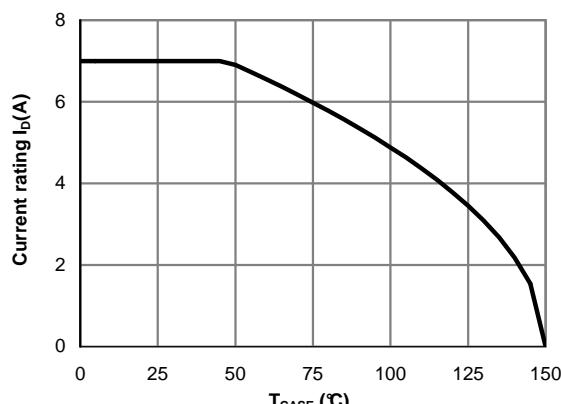
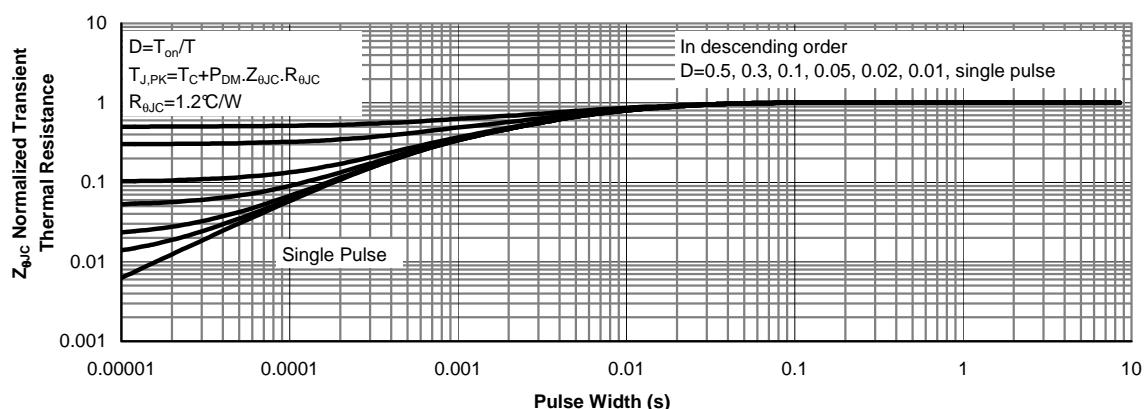
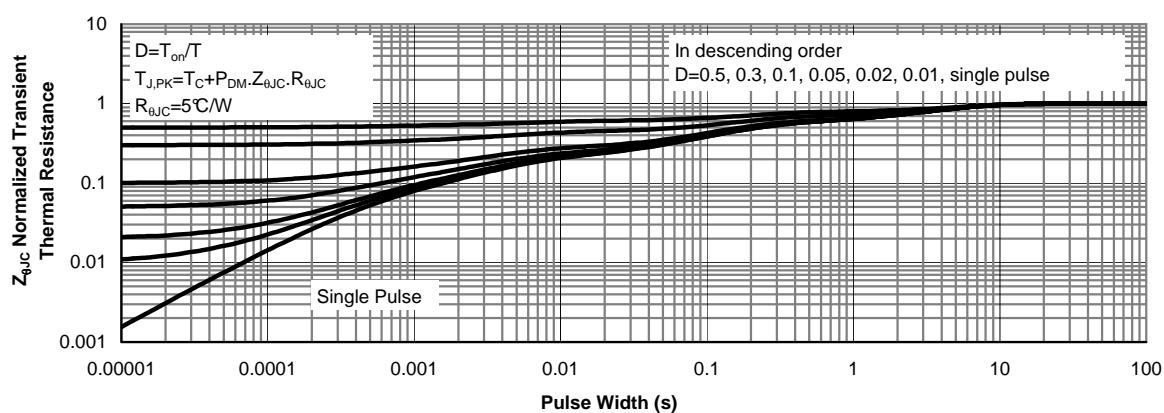
I. $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(\text{BR})DSS}$.

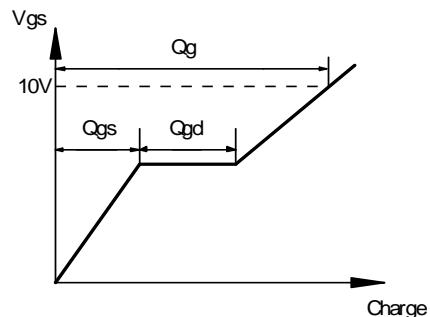
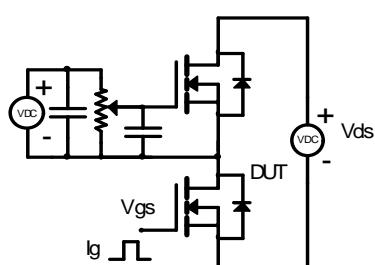
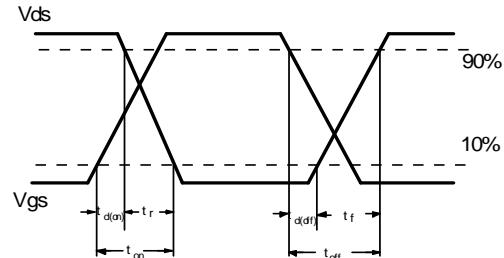
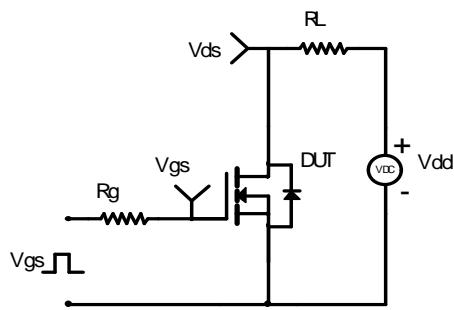
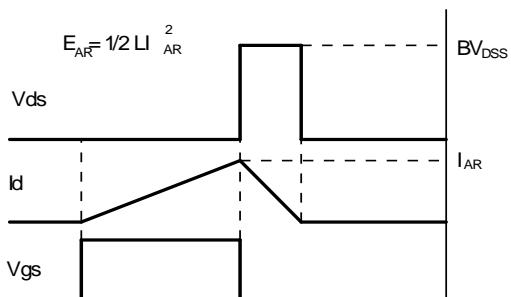
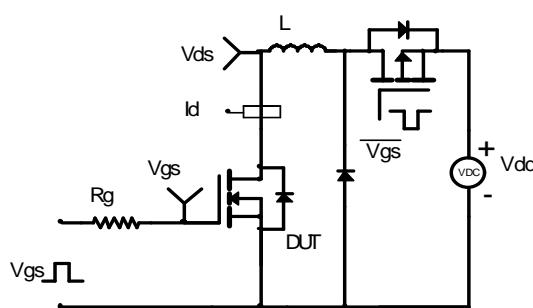
J. Wavesoldering only allowed at leads.

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics@25°C

Figure 2: On-Region Characteristics@125°C

Figure 3: Transfer Characteristics

Figure 4: On-Resistance vs. Drain Current and Gate Voltage

Figure 5: On-Resistance vs. Junction Temperature

Figure 6: Break Down vs. Junction Temperature

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Body-Diode Characteristics (Note E)

Figure 8: Gate-Charge Characteristics

Figure 9: Capacitance Characteristics

Figure 10: Coss stored Energy

Figure 11: Maximum Forward Biased Safe Operating Area for AOW7S65 (Note F)

Figure 12: Maximum Forward Biased Safe Operating Area for AOWF7S65 (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 13: Avalanche energy

Figure 14: Current De-rating (Note B)

Figure 15: Normalized Maximum Transient Thermal Impedance for AOW7S65 (Note F)

Figure 16: Normalized Maximum Transient Thermal Impedance for AOWF7S65 (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
